

Notice of References Cited

Application/Control No.

09/585,217

Applicant(s)/Patent Under
Reexamination
VLACHOS ET AL.

Examiner

Lance W. Sealey

Art Unit

2671

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,734,860	05-2004	Potter et al.	345/501
	B	US-6,674,433	01-2004	Junkins, Stephen	345/423
	C	US-6,163,319	12-2000	Peercy et al.	345/426
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 09/585,217	Applicant(s)/Patent Under Reexamination VLACHOS ET AL.	
	Examiner Lance W. Sealey	Art Unit 2671	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,488,684	01-1996	Gharachorloo et al.	345/423
	B	US-5,357,599	10-1994	Luken	345/627
	C	US-5,854,631	12-1998	Akeley et al.	345/419
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Owen, "Phong Shading Model for Scan-Line Graphics," 3/13/99, Association for Computing Machinery (ACM)
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.